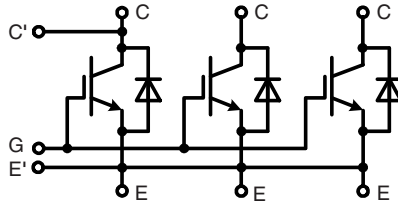


IGBT Module

Single switch

Short Circuit SOA Capability
Square RBSOA

$I_{C80} = 1800 \text{ A}$
 $V_{CES} = 1700 \text{ V}$
 $V_{CE(sat) \text{ typ.}} = 2.3 \text{ V}$



IGBT				
Symbol	Conditions	Maximum Ratings		
V_{CES} V	$V_{GE} = 0 \text{ V}$	1700		
V_{GES} V		± 20		
I_{C80} A	$T_C = 80^\circ\text{C}$	1800		
I_{CM} A	$t_p = 1 \text{ ms}; T_C = 80^\circ\text{C}$	3600		
Symbol	Conditions	Characteristic Values		
t_{SC} μs	$V_{CC} = 1000 \text{ V}; V_{CEM \text{ CHIP}} \leq 1700 \text{ V};$ ($T_{VJ} = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.	max.
$V_{CE(sat)}$ *	$V_{GE} \leq 15 \text{ V}; T_{VJ} \leq 125^\circ\text{C}$			
	$I_C = 1800 \text{ A}; V_{GE} = 15 \text{ V}; T_{VJ} = 25^\circ\text{C}$	2.3	2.6	V
	$T_{VJ} = 125^\circ\text{C}$	2.6	2.9	V
$V_{GE(th)}$	$I_C = 240 \text{ mA}; V_{CE} = V_{GE}$	4.5		6.5 V
I_{CES}	$V_{CE} = 1700 \text{ V}; V_{GE} = 0 \text{ V}; T_{VJ} = 125^\circ\text{C}$			120 mA
I_{GES}	$V_{CE} = 0 \text{ V}; V_{GE} = \pm 20 \text{ V}; T_{VJ} = 125^\circ\text{C}$			500 nA
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off}	Inductive load; $T_{VJ} = 125^\circ\text{C};$ $V_{GE} = \pm 15 \text{ V}; V_{CC} = 900 \text{ V};$ $I_C = 1800 \text{ A}; R_G = 0.82 \Omega;$ $L_o = 60 \text{ nH}$	285		ns
		230		ns
		950		ns
		240		ns
		530		mJ
		670		mJ
C_{ies} C_{oes} C_{res}	$V_{CE} = 25 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz}$	166		nF
		16.5		nF
		7.0		nF
Q_{ge}	$I_C = 1800 \text{ A}; V_{CE} = 900 \text{ V}; V_{GE} = \pm 15 \text{ V}$	15.1		μC
R_{thJC}				0.009 K/W

* Collector emitter saturation voltage is given at chip level

IXYS reserves the right to change limits, test conditions and dimensions.

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Diode

Symbol	Conditions	Maximum Ratings	
I_{F80}	$T_C = 80^\circ\text{C}$	1800	A
I_{FSM}	$V_R = 0\text{ V}; T_{VJ} = 125^\circ\text{C}; t_p = 10\text{ ms};$ half-sinewave	16500	A

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
V_F *	$I_F = 1800\text{ A}; T_{VJ} = 25^\circ\text{C}$ $T_{VJ} = 125^\circ\text{C}$	1.65	2.0	V
		1.70		V
I_{RM} t_{rr} Q_{RR} E_{rec}	$V_{CC} = 900\text{ V}; I_C = 1800\text{ A};$ $V_{GE} = \pm 15\text{ V}; R_G = 1.5\ \Omega; T_{VJ} = 125^\circ\text{C}$ Inductive load; $L_\sigma = 60\text{ nH}$	1470		A
		870		ns
		770		μC
		530		mJ
R_{thJC}			0.017	K/W

* Forward voltage is given at chip level

Module

Symbol	Conditions	Maximum Ratings	
T_{JM}	max. junction temperature	+150	$^\circ\text{C}$
T_{VJ}	Operating temperature	-40...+125	$^\circ\text{C}$
T_{stg}	Storage temperature	-40...+125	$^\circ\text{C}$
V_{ISOL}	50 Hz	4000	V~
M_d	Mounting torque	Base-heatsink, M6 screws	4 - 6 Nm
		Main terminals, M8 screws	8 - 10 Nm

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
d_A	Clearance distance	terminal to base	23	mm
		terminal to terminal	19	mm
d_s	Surface creepage distance	terminal to base	33	mm
		terminal to terminal	33	mm
L_σ	Module stray inductance, C to E terminal		10	nH
$R_{term-chip}$ *)	Resistance terminal to chip		0.085	m Ω
R_{thCH}	per module; λ grease = 1 W/m \cdot K		0.006	K/W
Weight			1500	g

*) $V = V_{CE(sat)} + R_{term-chip} \cdot I_C$ resp. $V = V_F + R_{term-chip} \cdot I_F$

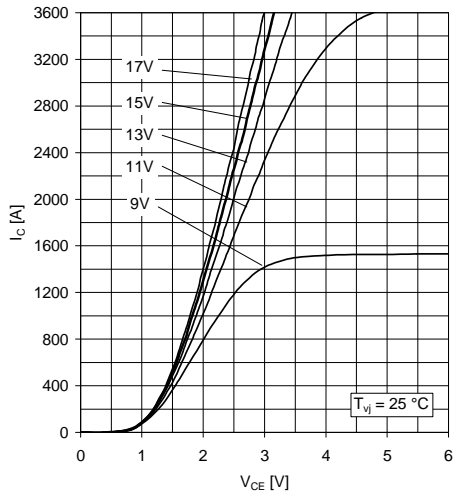


Fig. 1 Typical output characteristics, chip level

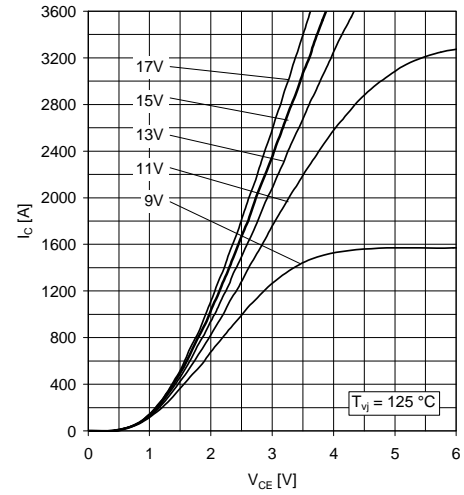


Fig. 2 Typical output characteristics, chip level

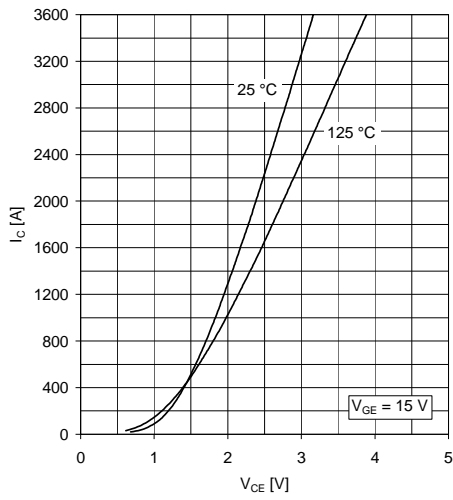


Fig. 3 Typical onstate characteristics, chip level

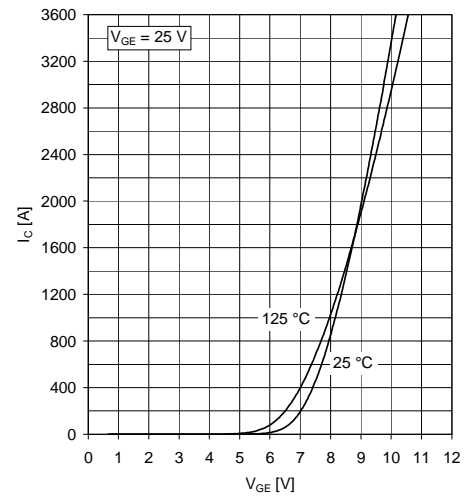


Fig. 4 Typical transfer characteristics, chip level

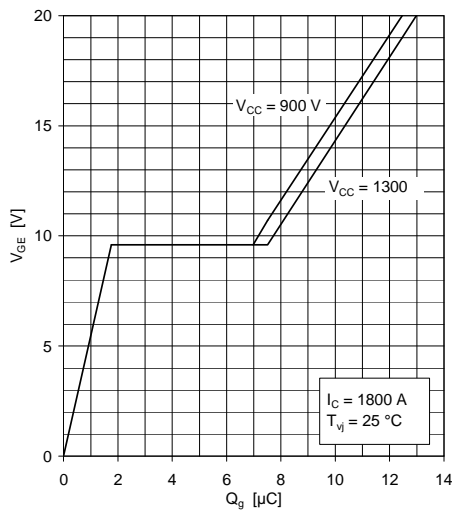


Fig. 5 Typical gate charge characteristics

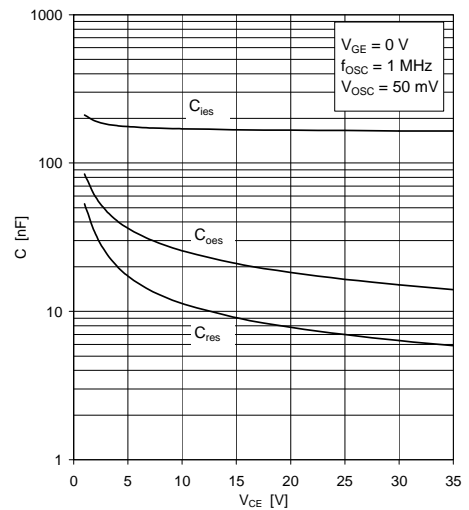


Fig. 6 Typical capacitances vs collector-emitter voltage

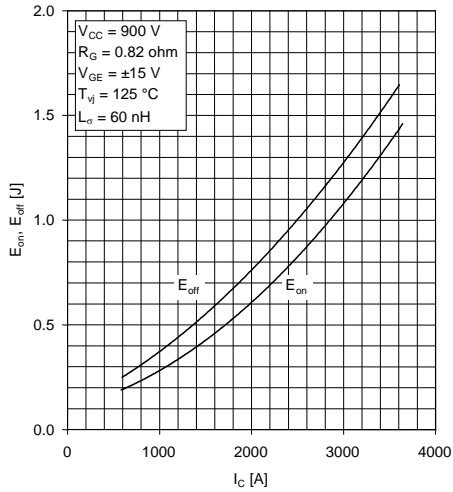


Fig. 7 Typical switching energies per pulse vs collector current

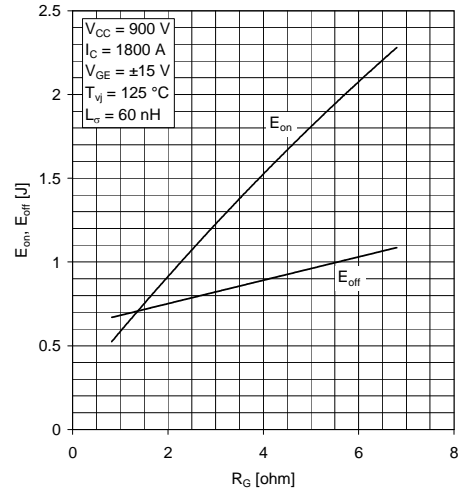


Fig. 8 Typical switching energies per pulse vs gate resistor

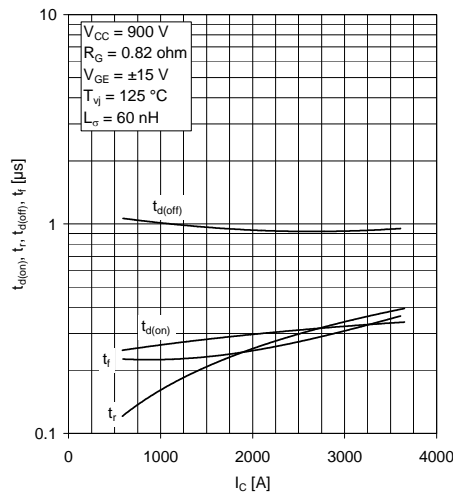


Fig. 9 Typical switching times vs collector current

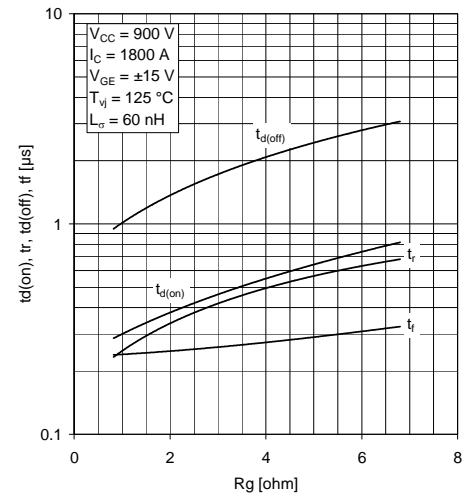


Fig. 10 Typical switching times vs gate resistor

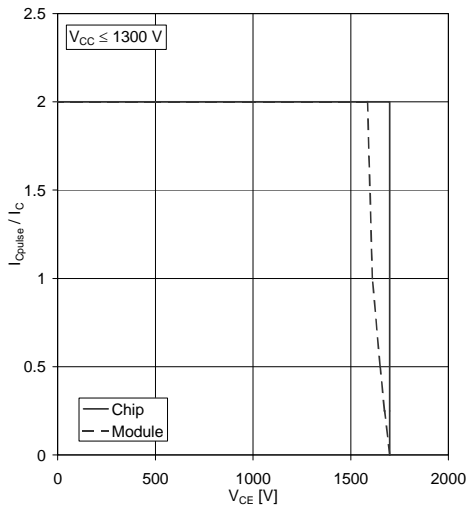


Fig. 11 Turn-off safe operating area (RBSOA)

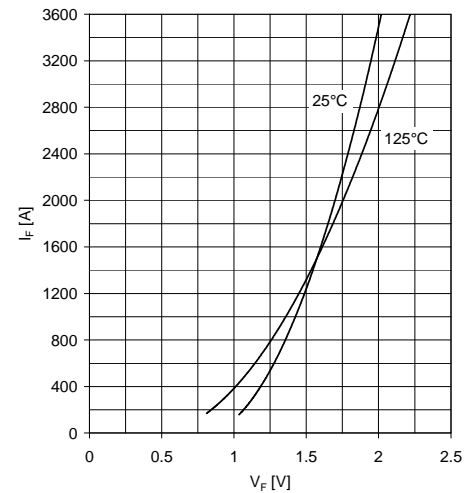


Fig. 12 Typical diode forward characteristics, chip level

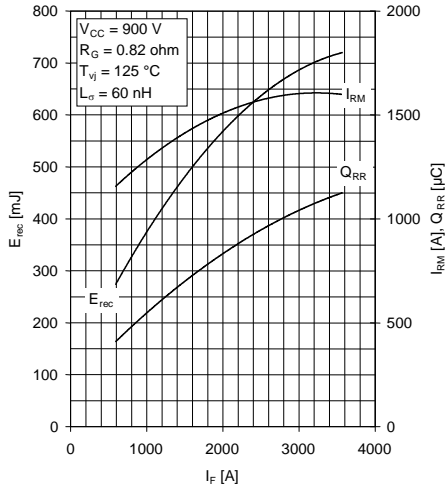


Fig. 13 Typical reverse recovery characteristics vs forward current

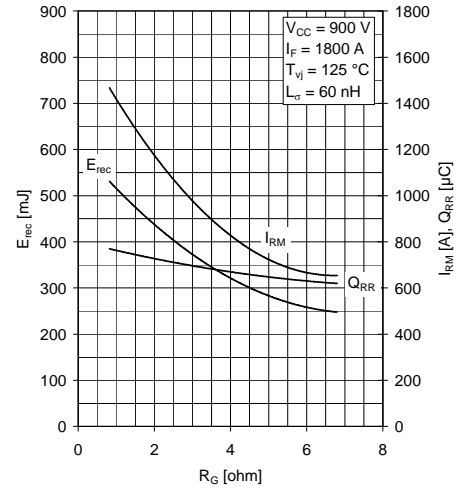


Fig. 14 Typical reverse recovery characteristics vs gate resistor

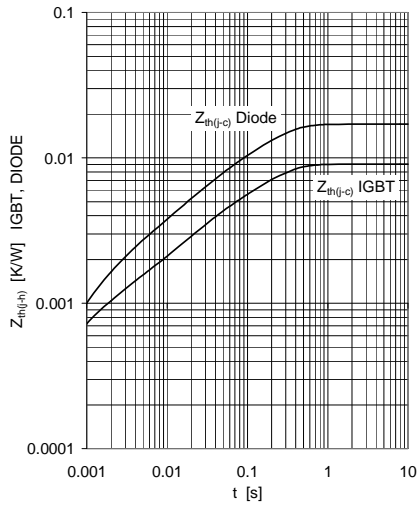
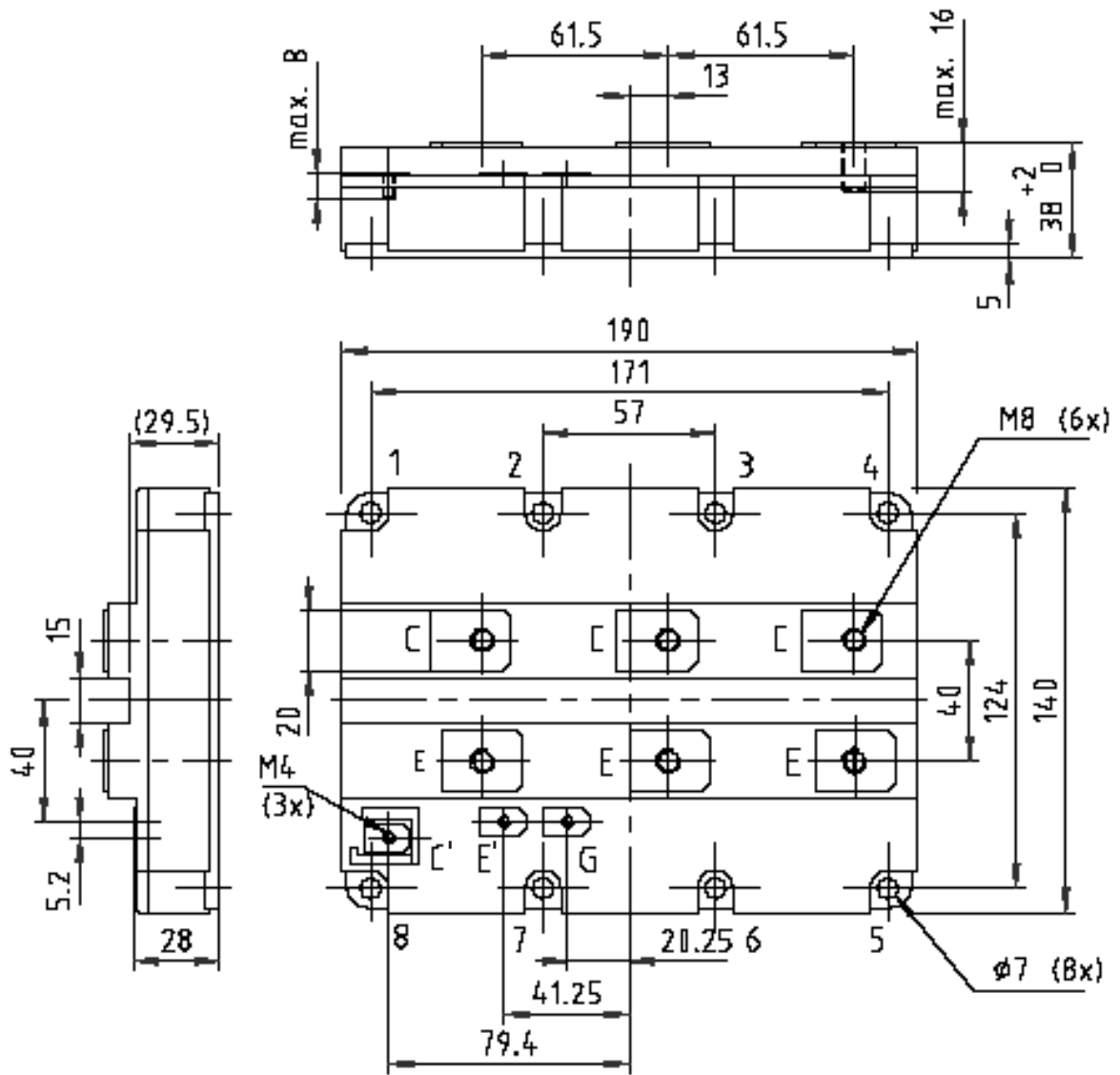


Fig. 15 Thermal impedance vs time

$$Z_{th(j-c)}(t) = \sum_{i=1}^n R_i (1 - e^{-t/\tau_i})$$

	i	1	2	3	4
IGBT	R _i (K/kW)	5.97	1.99	0.619	0.465
	τ _i (ms)	179	22	2.4	0.54
DIODE	R _i (K/kW)	11.1	3.36	1.27	1.34
	τ _i (ms)	189	30	7.4	1.4

Outline drawing



Note: all dimensions are shown in mm